

Search Notes



Application/Control No.

10/757,782

Examiner

José V. Chen

Applicant(s)/Patent under Reexamination

WUNSH ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	25 26 27	9/14/15	JLC
	12		
	14		
	13		
	40		
	161		
206	769		
	770		
	326		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Long Base Gr. For 1007-ART	9/20/15	JLC